	ESC	<u>;C</u>	D	OCUMENT	CHANGE REQUEST
DCR number	673 Changes required for: General		Originator: Steve Thacker		
Date: 2013/12	2/05 Date sent: 2011/08/02			Organisation: ESCC Executive Secretariat	
Status: IMPLE					
Title:	Generic Specification for Relays Electromagnetic Latching				
Number:	3602 Issue: 2				
Other documen	ts affected:				
Page:					
all pages					
Paragraph:					
all paras					
Original wording	g:				
Total reformat/re-write of ESCC Generic Specification 3602 issue 2 as part of the ongoing conversion to the latest ESCC format.					
Proposed wording:					
The Generic Specification is proposed to be extensively amended to incorporate various policy, technical & editorial amendments & corrections in order to bring it in line with other ESCC Generic Specifications that have already been converted to the new ESCC format, as well as reflect the latest technical baseline ESCC generic specification requirements for latching relays.					
The layout, forr issue 6 per DC The proposed t amendments, c various other of 356/ 358/ 359/	mat and general str Rs 149, 236, 286, 3 echnical content of discussed and agre pen DCRs. This DC 360) which shall no	ucture, and edit 313 & 399 (all a ESCC3602 dra ed by ESA, CN CR effectively re ow be withdrawr	orial content of pproved). aft 3C is based ES and various eplaces all thos n.	3602 issue 3 dra on the current cor relay manufactur e other DCRs (DC	ft C are based closely on ESCC 5000 Intent of ESCC3602 issue 2 plus Pers since 2006, as were included within CRs 287/ 345/ 346/ 347/ 350/ 352/ 354/
This DCR summarises all the amendments to 3602 issue 2, plus identifies the additional editorial & technical changes to ESCC 3602 issue 2 not already generally detailed and justified by approved DCRs 149/236/286/313/399.					
For full details of the proposed contents of ESCC 3602 issue 3 see the attached draft Generic specification ESCC 3602 issue 3 draft C.					
Change Details:					
A) Main General Changes (similar to those already incorporated into ESCC5000 issue 6):					
1) The SCC testing level B has been deleted; there is still only a single ESCC testing level, equivalent to old SCC level B,					

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but it is not given a spe	ecific designat	ion.		
 2) Qualification and Lot Acceptance Testing charts have been incorporated, with some modifications, into a single Chart F4, Qualification and Periodic Tests. Modifications include: Periodic testing is mandatory for ESCC qualified components with a defined testing schedule. Lot Acceptance Testing has been deleted but an Orderer option for similar Lot Validation Testing, for procurement, has been added. Lot Validation Testing is not mandatory and will only be done if specifically stipulated by the Orderer in their PO. The requirement for LAT level 3 as a minimum for non-qualified component procurement is removed. No failures are allowed during Chart F4 testing. 				
3) Introduction of Tech	nology Flow (Qualification per ESCC N	No. 25400 to the Gene	ric spec.
4) Introduction of ESC and Procurement of Ur	C 23100 (ESC nqualified Cor	CC Recommendations o nponents) to the generic	n the use of the ESCC spec.	Specification System for the Evaluation
5) The Generic Specifi as for ESCC Qualified	cation has be components.	en made applicable and	fully usable for procur	rement of unqualified components as well
6) Clarification that the	term PID is s	pecific only to ESCC qu	alified components.	
7) The minimum requir sheet.	ed delivered o	documentation to the cu	stomer for procuremer	nt is a Certificate of Conformity & a Cover
8) Clarification of Customer Source inspection options for Pre-encapsulation CSI (Pre-Cap) & Final CSI (Buy-Off), where the Customer & Manufacturer mutually agree what is to be performed and how much notification is required.				
9) The maximum allow	red delay for L	ot failure notification (pr	ovided by the Manufac	cturer) is now 5 working days (was 2).
10) Para 5 & Chart F2,	, Production C	control/Special In-Proces	ss Controls, replaces P	Paras 5 & 6 and Chart II.
11) The General Flow	Chart I is repl	aced by Chart F1; It clar	ifies the flow of compo	onents for Procurement.
12) Chart II Screening	and Electrical	Measurements, has be	en replaced by Chart F	F3, Screening Tests.
13) When using the ES component number, th with space application. requirements of Chart that cannot meet the C	SCC System to e Manufacture As such, the F4. According Chart F4 testin	o procure components f er should possess a ma user expectation should ly the requirement place g is extended to unquali	rom an unqualified soun nufacturing and quality the that parts would be ad on qualified sources fied sources.	arce and marking the parts with the ESCC assurance system that is compatible e compatible with passing the testing s to not knowingly supply components
14) Material outgassing	g reference do	ocument is corrected to	be ECSS-Q-ST-70-02.	
15) Para 9.23 & Chart	II, Dimension	Check is performed on	3 samples instead of 5	5.



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 Delete AC method of Amend test current Amend Test voltage 	option. to be as specif to be a maxim	ied in the detail specifica num value (6V max)	tion (within specified li	imits)
23) Para 9.3.4, Latch Test method is amen added Delete figure I	, Reset and Bo ded (see the a	unce Times tached 3602 draft 3C Pa	ara 8.3.1.4 for full deta	ils). Definition of Contact Bounce is
24) Para 9.4.1, Seal ⁻ Test method is amen - Test condition D is a - For test condition B,	Fest Gross Lea ded including t added as an op Water temper	k he following main change tion ature and pressure value	es (see the attached 3 es are specified (25C 8	602 draft 3C Para 8.4.2 for full details): & <8465Pa, respectively)
25) Para 9.4.2, Seal ⁻ Test method is amen - Pressure value is sp - During Charts F2 & respectively. - During Chart F4 tes	Fest Fine Leak ded including t becified (400kP F3 testing, dur ting, the measu	he following main change a) ation of pressurisation ar ured leak rate shall be re	es (see the attached 3 nd recovery is amende corded against compo	602 draft 3C Para 8.4.1 for full details): ed to be 2 hours and 30 minutes onent serial number.
26) Para 9.6, Vibratio Test method is amen - Maximum vibration t	n Scan ded including t frequency is ar	he following main chango nended to be 3000Hz.	es (see the attached 3	602 draft 3C Para 8.6 for full details):
27) Para 9.7, Electric The specific 1 hour se	al Measuremei oak requiremer	nts at High & Low temper nt before measurements	ratures is amended to be a ge	eneral requirement for stabilisation.
28) Para 9.8 & Chart The Low Level Test p as specified in the ap 100ohm, unless other	III, Low Level ⁻ performed at Hi plicable Detail rwise specified	Fest gh, Low and Room temp specifications. The maxi in the Detail Specificatic	peratures is renamed a mum contact resistanc on.	as Run-in and the test temperature(s) is ce allowed during the test is fixed at
29) Para 9.9 & Chart	III, Internal Mo	isture test is deleted.		
30) Para 9.10, Vibrati Test method is amen - test is renamed as L - Maximum vibration f - After the test electric specified.	on ded including t .ow Level Sine frequency is ar cal measureme	he following main change Vibration nended to be 3000Hz. ents shall be performed a	es (see the attached 3 as specified in the deta	602 draft 3C Para 8.8.1 for full details): all specification including the drift values if
31) Para 9.11, Mecha	anical Shock			

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Test method is amen - test is renamed as I - Test condition is fixe - After the test electri specified.	ded including t .ow Level Mecl ed at test condi cal measureme	he following main chang hanical Shock ition C (100g, 6ms half-s ents shall be performed a	es (see the attached 3 ine) (was as specified as specified in the deta	602 draft 3C Para 8.9.1 for full details): in the detail specification) il specification including the drift values if
32) Para 9.12.1, Ove Test method is amen - Contact overload cu - The Voltage Drop a - The Voltage Drop s - Reference to Norma	load (for Relay ded including t rrent shall be a cross closed co hall be monitor ally Closed and	ys <5A) he following main chang as specified in the detail ontacts shall be as speci ed for 40% minimum of e I Normally Open contacts	es (see the attached 3 specification (was fixed fied in the Detail Speci each ON and OFF perions is deleted.	602 draft 3C Para 8.16.1 for full details): d at 2xRated Resistive Current). ification (was 5% of applied voltage) iod during the switching cycle (was 50%)
 33) Para 9.12.2, Ove Test method is amen Contact overload cu The Voltage Drop a Reference to Norma 	rload (for Relay ded including t irrent shall be a cross closed co ally Closed and	ys 5A to 20A) he following main chang as specified in the detail ontacts shall be as speci I Normally Open contacts	es (see the attached 3 specification (was fixe fied in the Detail Speci s is deleted.	602 draft 3C Para 8.16.2 for full details): d at 4xRated Resistive Current). ification (was 10% of applied voltage)
 34) Para 9.12.3, Ove Test method is amen Contact overload cu The Voltage Drop a The Voltage Drop s Reference to Norma 	load (for Relay ded including t rrent shall be a cross closed co hall be monitor ally Closed and	ys >20A) he following main chang as specified in the detail ontacts shall be as speci ed for 40% minimum of e I Normally Open contacts	es (see the attached 3 specification (was fixed fied in the Detail Speci each ON and OFF peri s is deleted.	602 draft 3C Para 8.16.3 for full details): d at 2xRated Resistive Current). ification (was 10% of applied voltage) iod during the switching cycle (was 50%)
35) Para 9.13, Therm Measurement of Insu measurements as sp	al Shock lation resistanc ecified in the de	ce during the 5th cycle (a etail specification are ad	at each temperature ex ded.	treme) is deleted. Final electrical
36) Para 9.16.1, Inter Test method is amen - The Voltage Drop a	mediate Curre ded including t cross closed co	nt (for Relays <5A) he following main chang ontacts shall be as speci	es (see the attached 3 fied in the Detail Speci	602 draft 3C Para 8.13.1 for full details): ification (was 300mV maximum)
37) Para 9.16.2, Inter Test method is amen - The Voltage Drop a - The number of cycle - Reference to Norma	mediate Curre ded including t cross closed co as of operation ally Closed and	nt (for Relays 5A to 20A) he following main chang ontacts shall be as speci applied during the test s Normally Open contacts) es (see the attached 3 fied in the Detail Speci shall be 5000 (was 500 s is deleted. Contacts I	602 draft 3C Para 8.13.2 for full details): ification (was per Table in Para 9.16.2) 00) loads are applied equally to all contacts.
38) Para 9.16.3, Inter Test method is amen - The Voltage Drop a	mediate Curre ded including t cross closed co	nt (for Relays >20A) he following main chang ontacts shall be as speci	es (see the attached 3 fied in the Detail Speci	602 draft 3C Para 8.13.3 for full details): ification (was 200mV maximum)

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- The number of cycle - Reference to Normal	s of operation lly Closed and	applied during the test s Normally Open contacts	hall be 5000 (was 500 s is deleted. Contacts l	00) loads are applied equally to all contacts.
39) Para 9.19.1, Resis Test method is amend - The test current (Cor Specification (referenc - The Voltage Drop ac	stive Life led including th ntact Load) co ce to Table 5(b ross closed co	he following main chang ndition is fixed at Rated b) is deleted) ontacts shall be as specif	es (see the attached 3 Resistive Load Contac fied in the Detail Speci	602 draft 3C Para 8.11.3 for full details): ct Current as specified in the Detail ification (was 10% of applied voltage)
40) Para 9.19.2, Low I Test method is amend - Test is renamed Low - The test temperature temperature).	Level Load an led including th / Level Life e shall be room	d Mechanical Life (Relay he following main chang n ambient (was a mixture	vs <5A) es (see the attached 3 e of both Maximum Op	602 draft 3C Para 8.11.1 for full details): erating temperature and room ambient
41) Para 9.19.3, Induc Test method is amenc - The Voltage Drop ac	ctive Life (Rela led including th ross closed co	ys >=5A) he following main chang ontacts shall be as speci	es (see the attached 3 fied in the Detail Speci	602 draft 3C Para 8.11.2 for full details): ification (was 10% of applied voltage)
43) Para 9.22, Encaps	sulation is dele	eted.		
44) Para 10.8 & 10.9, The measured leak ra the attached 3602 dra	Data for Quali te results from ft 3C Paras 9.	fication Tests & LAT Chart F4 tests shall be 7.1, 9.7.2 & 9.7.3 for det	recorded against com ails).	ponent serial number and provided (see
45) Para 7.4.1 Lot Fai Only electrical parame Electrical Measuremen failures per Para 7.2.3	lure During 10 eter limit failure nts during Scre).	0% Testing es during Room Tempera eening Tests shall count	ature Electrical Measu towards percent defe	rements & High and Low Temperatures ctive lot failure (i.e. excluding other
46) Para 10.6. Final P Room Temperature El read & record against	roduction Test lectrical Meast serial number	t Data (Chart II) urements (during Specia	I In-Process Controls i	in 3602 issue 3 draft C Chart F2), shall be
Justification:				
All changes have been completeness, simplifi interpretation of the sp	n defined and cation, harmo pecification and	included to serve the pu nisation and consistency d its requirements whilst	rposes of technical imp 7. The aim is to simplify maintaining an efficier	provement, clarification, accuracy, y and improve the content and nt and acceptable technical baseline.
Additional mechanical	tests (i.e. Rar	ndom Vibration, High Lev	vel Sine Vibration, Higl	h Level Mechanical Shock) have been

introduced into Chart F4 to answer the requirements of new space launchers.

ESCC D	OCUMENT CHANGE REQUEST
DCR number 673 Changes required for: Ge	eneral Originator: Steve Thacker
Date: 2013/12/05 Date sent: 2011/08/02	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED	
All technical changes have been defined and agreed by ESA & ESCC 3602 draft 3C is written to closely follow the layout, forma justifications for the related policy and editorial changes given in DCRs 149, 236, 286, 313, 399) also apply to this DCR. Note – All ESCC Detail specifications for non-latching relays (36 with the contents of ESCC Generic Specification 3602 issue 3 p implemented into each Detail specification resulting from the charge specification resulting from the charge specification resulting from the charge specification and the charge specification for the charge specificati	CNES. at and content of the latest ESCC 5000 issue 6. The all other previous DCRs related to ESCC 5000 issue 6 (i.e. 302/xxx) will need to be converted to make them consistent ber this DCR. The main technical changes to be anges in this DCR are as follows:
 Implementation of 'Run-in' (replacing 'Miss Test'); affecting Tal Implementation of Drift Parameters during Screening (over 'Ru applicable to each Detail Spec; affecting Table 4. Specification of test current for measurement of contact resista Implementation of addition environmental & Mechanical test revibration & High Level Mechanical Shock); affecting Table 6. Implementation of Drift Parameters during Qualification and Perfor the following tests, as applicable to each Detail Spec: Vibration Mechanical Shock Overload Intermediate Current Operating Life Resistive (= Resistive Life) Operating Life Low Level Load and Mechanical Shock (= Low o Random Vibration (new test) High Level Mechanical Shock (new test) 	ble 4 & Table 5(a). In-in')(i.e. Latch Voltage & Reset Voltage drift values), as ance; affecting Table 2. Iquirements (i.e. Random Vibration, High Level Sine eriodic tests (i.e. Latch Voltage & Reset Voltage drift values)

Attachments:
3602_draft_3d_for_final_review.pdf, 3602_draft_3c.pdf, null
Modifications:
N/A
Approval signature:
- Car
Date signed:
2013-12-05